

Thickness Gauge (Fe & NFe) UEE920S

Product Description

The instrument is a portable Non-destructive testing instrument. It can quickly, accurately measure the thickness of the coating with no damage. By using different measuring probes, it can meet the needs of a variety of measurement. The instrument is widely used in manufacturing, metal processing industry, chemical industry, commodities inspection, and other areas.



Standards

- ISO 2178-2016
- ISO 2360-2017
- JJG 818–2018

Technical Specification

- Using both the magnetic and eddy current method, can measure the thickness of the magnetic non-magnetic coating on metal substrates and measurable non-magnetic thickness of the conductive coating on metal substrates.
- Two measuring modes: Single / Continuous
- The instrument carried the following standards: ISO 2178–2016 Non-magnetic coatings on magnetic substrates-Measurement of coating thickness- Magnetic method ISO 2360–2017 Non-conductive coatings on Non-magnetic electrical conductive basis metals- Measurement of coating thickness- Amplitude sensitive eddy current method JJG 818–2018 Magnetic and Eddy Current Measuring Instrument for Coating Thickness
- Three work modes Fe / NFe / Auto
- Five statistics: Average, maximum and minimum values, test times, the standard deviation
- Single point and Two points calibration methods can be applied to the gauge; And the system error of the probe can be corrected with the basic probe calibration method
- Storage functions: Can store 500 measurements data in total
- Limit set: Automatically alarm while measurements beyond the limit
- Low voltage indicator
- Operation process have hum tips
- Error prompt, screen display or hum errors



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- Two ways to shutdown mode: Manual shutdown mode and automatic shutdown mode
- Can be connected with computer by installing the software, to realize data transmission, fast and convenient

Probe Type		F	Ν
Measuring principle		Magnetic induction	Eddy current
Measuring range		0~1500 µm	0~1500 µm
Resolution		±0.01 μm	±0.01 μm
Accuracy	Zero calibration	±(2%H+1)m	±(2%H+1)m
	Two point calibration	[(1~2)%H+1]m	[(1~2)%H+1]m
Measuring Condition	Min. radius of curvature	Cx. 1.5 mm	Cx. 3 mm
	Min. radius of area	Ø7 mm	Ø5 mm
	Critical thickness of plate	0.5 mm	0.3 mm



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Main Technical Parameters

Packing List:

- Main unit
- Probe (FN)
- Standard specimens (5 pcs)
- Substrate (FN)
- Packing box
- Instruction manual
- Guarantee card
- PC Software
- Other probes (optional)

Disclaimer

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